

Welcome to [E-XFL.COM](#)

### **Understanding Embedded - FPGAs (Field Programmable Gate Array)**

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

#### **Details**

Product Status	Obsolete
Number of LABs/CLBs	1377
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	228
Number of Gates	10000
Voltage - Supply	4.5V ~ 5.5V
Mounting Type	Through Hole
Operating Temperature	-55°C ~ 125°C (TJ)
Package / Case	257-BCPGA
Supplier Device Package	257-CPGA (50x50)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/microsemi/a14100a-1pg257b">https://www.e-xfl.com/product-detail/microsemi/a14100a-1pg257b</a>

## Plastic Device Resources

Device Series	Logic Modules	Gates	User I/Os							
			PL84	PQ100	PQ160	PQ/RQ208	VQ100	TQ176	BG225*	BG313
A1415	200	1500	70	80	–	–	80	–	–	–
A1425	310	2500	70	80	100	–	83	–	–	–
A1440	564	4000	70	–	131	–	83	140	–	–
A1460	848	6000	–	–	131	167	–	151	168	–
A14100	1377	10000	–	–	–	175	–	–	–	228

Note: \*Discontinued

## Hermetic Device Resources

Device Series	Logic Modules	Gates	User I/Os							
			PG100*	PG133*	PG175*	PG207	PG257	CQ132	CQ196	CQ256
A1415	200	1500	80	–	–	–	–	–	–	–
A1425	310	2500	–	100	–	–	–	100	–	–
A1440	564	4000	–	–	140	–	–	–	–	–
A1460	848	6000	–	–	–	168	–	–	168	–
A14100	1377	10000	–	–	–	–	228	–	–	228

Note: \*Discontinued

Contact your local Microsemi SoC Products Group (formerly Actel) representative for device availability:  
<http://www.microsemi.com/soc/contact/default.aspx>.

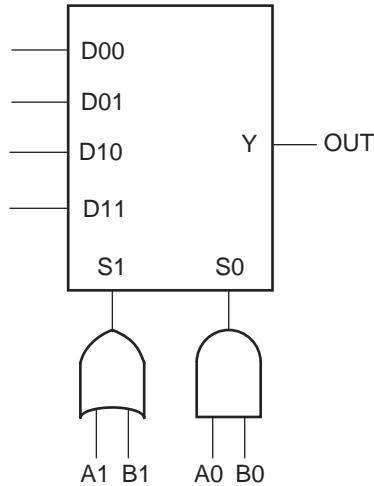
**Table 1-1 • Chip-to-Chip Performance (worst-case commercial)**

Device and Speed Grade	t <sub>CKHS</sub> (ns)	t <sub>TRACE</sub> (ns)	t <sub>INSU</sub> (ns)	Total (ns)	MHz
A1425A -3	7.5	1.0	1.8	10.3	97
A1460A -3	9.0	1.0	1.3	11.3	88
A1425A -2	7.5	1.0	2.0	10.5	95
A1460A -2	9.0	1.0	1.5	11.5	87
A1425A -1	9.0	1.0	2.3	12.3	81
A1460A -1	10.0	1.0	1.8	12.8	78
A1425A STD	10.0	1.0	2.7	13.7	73
A1460A STD	11.5	1.0	2.0	14.5	69

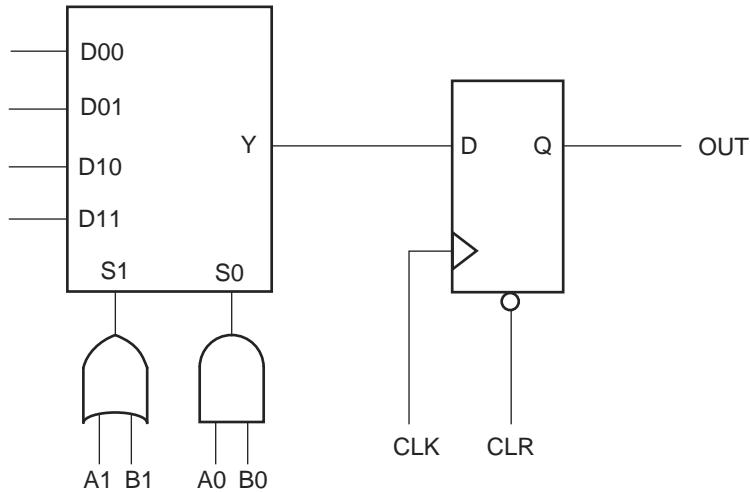
Note: The -2 and -3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.

## Logic Modules

ACT 3 logic modules are enhanced versions of the 1200XL family logic modules. As in the 1200XL family, there are two types of modules: C-modules and S-modules (Figure 2-2 and Figure 2-3). The C-module is functionally equivalent to the 1200XL C-module and implements high fanin combinatorial macros, such as 5-input AND, 5-input OR, and so on. It is available for use as the CM8 hard macro. The S-module is designed to implement high-speed sequential functions within a single module.



**Figure 2-2 • C-Module Diagram**



**Figure 2-3 • S-Module Diagram**

S-modules consist of a full C-module driving a flip-flop, which allows an additional level of logic to be implemented without additional propagation delay. It is available for use as the DFM8A/B and DLM8A/B hard macros. C-modules and S-modules are arranged in pairs called module-pairs. Module-pairs are arranged in alternating patterns and make up the bulk of the array. This arrangement allows the placement software to support two-module macros of four types (CC, CS, SC, and SS). The C-module implements the following function:

$$Y = !S1 * !S0 * D00 + !S1 * S0 * D01 + S1 * !S0 * D10 + S1 * S0 * D11$$

EQ 1

where:  $S0 = A0 * B0$  and  $S1 = A1 + B1$

The I/O module output Y is used to bring Pad signals into the array or to feed the output register back into the array. This allows the output register to be used in high-speed state machine applications. Side I/O modules have a dedicated output segment for Y extending into the routing channels above and below (similar to logic modules). Top/Bottom I/O modules have no dedicated output segment. Signals coming into the chip from the top or bottom are routed using F-fuses and LVTs (F-fuses and LVTs are explained in detail in the routing section).

## I/O Pad Drivers

All pad drivers are capable of being tristate. Each buffer connects to an associated I/O module with four signals: OE (Output Enable), IE (Input Enable), DataOut, and DataIn. Certain special signals used only during programming and test also connect to the pad drivers: OUTEN (global output enable), INEN (global input enable), and SLEW (individual slew selection). See Figure 2-5.

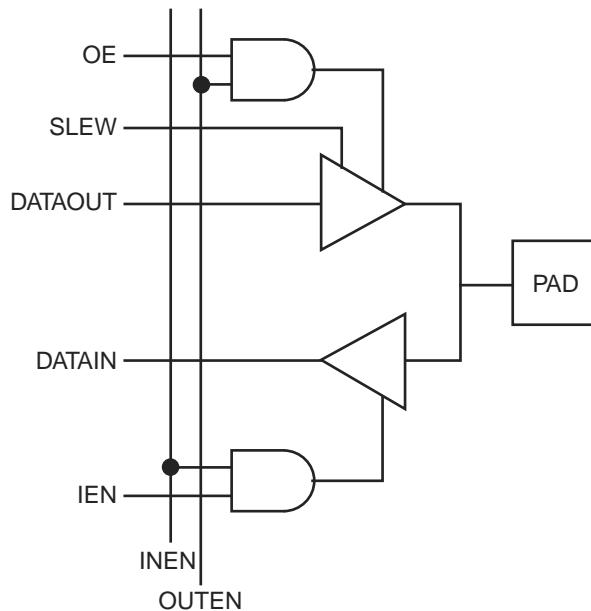


Figure 2-5 • Function Diagram for I/O Pad Driver

## Special I/Os

The special I/Os are of two types: temporary and permanent. Temporary special I/Os are used during programming and testing. They function as normal I/Os when the MODE pin is inactive. Permanent special I/Os are user programmed as either normal I/Os or special I/Os. Their function does not change once the device has been programmed. The permanent special I/Os consist of the array clock input buffers (CLKA and CLKB), the hard-wired array clock input buffer (HCLK), the hard-wired I/O clock input buffer (IOCLK), and the hard-wired I/O register preset/clear input buffer (IOPCL). Their function is determined by the I/O macros selected.

## Clock Networks

The ACT 3 architecture contains four clock networks: two high-performance dedicated clock networks and two general purpose routed networks. The high-performance networks function up to 200 MHz, while the general purpose routed networks function up to 150 MHz.

### **Module Output Connections**

Module outputs have dedicated output segments. Output segments extend vertically two channels above and two channels below, except at the top or bottom of the array. Output segments twist, as shown in Figure 10, so that only four vertical tracks are required.

### **LVT Connections**

Outputs may also connect to nondedicated segments called Long Vertical Tracks (LVTs). Each module pair in the array shares four LVTs that span the length of the column. Any module in the column pair can connect to one of the LVTs in the column using an FF connection. The FF connection uses antifuses connected directly to the driver stage of the module output, bypassing the isolation transistor. FF antifuses are programmed at a higher current level than HF, VF, or XF antifuses to produce a lower resistance value.

### **Antifuse Connections**

In general every intersection of a vertical segment and a horizontal segment contains an unprogrammed antifuse (XF-type). One exception is in the case of the clock networks.

### **Clock Connections**

To minimize loading on the clock networks, a subset of inputs has antifuses on the clock tracks. Only a few of the C-module and S-module inputs can be connected to the clock networks. To further reduce loading on the clock network, only a subset of the horizontal routing tracks can connect to the clock inputs of the S-module.

## **Programming and Test Circuits**

The array of logic and I/O modules is surrounded by test and programming circuits controlled by the temporary special I/O pins MODE, SDI, and DCLK. The function of these pins is similar to all ACT family devices. The ACT 3 family also includes support for two Actionprobe® circuits, allowing complete observability of any logic or I/O module in the array using the temporary special I/O pins, PRA and PRB.

### 3.3 V Operating Conditions

**Table 2-5 • Absolute Maximum Ratings<sup>1</sup>, Free Air Temperature Range**

Symbol	Parameter	Limits	Units
VCC	DC supply voltage	-0.5 to +7.0	V
VI	Input voltage	-0.5 to VCC + 0.5	V
VO	Output voltage	-0.5 to VCC + 0.5	V
IIO	I/O source sink current <sup>2</sup>	±20	mA
T <sub>STG</sub>	Storage temperature	-65 to +150	°C

Notes:

1. Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Device should not be operated outside the recommended operating conditions.
2. Device inputs are normally high impedance and draw extremely low current. However, when input voltage is greater than VCC + 0.5 V for less than GND -0.5 V, the internal protection diodes will forward bias and can draw excessive current.

**Table 2-6 • Recommended Operating Conditions**

Parameter	Commercial	Units
Temperature range*	0 to +70	°C
Power supply tolerance	3.0 to 3.6	V

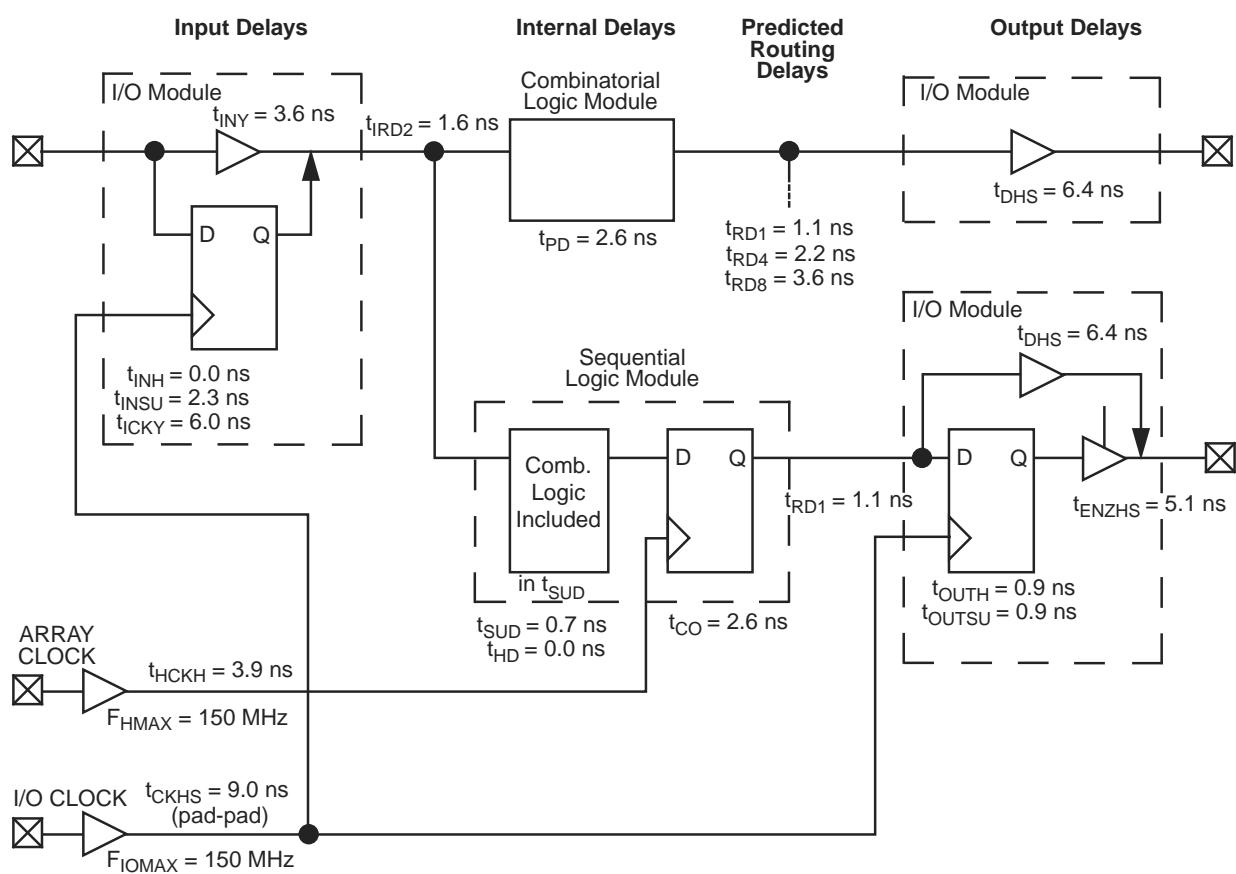
Note: \*Ambient temperature ( $T_A$ ) is used for commercial.

**Table 2-7 • Electrical Specifications**

Parameter	Commercial		Units	
	Min.	Max.		
VOH <sup>1</sup>	IOH = -4 mA	2.15	V	
	IOH = -3.2 mA	2.4	V	
VOL <sup>1</sup>	IOL = 6 mA	0.4	V	
VIL	-0.3	0.8	V	
VIH	2.0	VCC + 0.3	V	
Input transition time t <sub>R</sub> , t <sub>F</sub> <sup>2</sup>	VI = VCC or GND	-10	+10	µA
C <sub>IO</sub> I/O Capacitance <sup>2,3</sup>		10	pF	
Standby current, ICC <sup>4</sup> (typical = 0.3 mA)		0.75	mA	
Leakage current <sup>5</sup>	-10	10	µA	

1. Only one output tested at a time. VCC = minimum.
2. Not tested; for information only.
3. Includes worst-case 84-pin PLCC package capacitance. VOUT = 0 V, f - 1 MHz.
4. Typical standby current = 0.3 mA. All outputs unloaded. All inputs = VCC or GND.
5. VO, VIN = VCC or GND

## ACT 3 Timing Model



Note: Values shown for A1425A –1 speed grade device.

Figure 2-10 • Timing Model

### Timing Derating

ACT 3 devices are manufactured in a CMOS process. Therefore, device performance varies according to temperature, voltage, and process variations. Minimum timing parameters reflect maximum operating voltage, minimum operating temperature, and best-case processing. Maximum timing parameters reflect minimum operating voltage, maximum operating temperature, and worst-case processing.

**Table 2-15 • Timing Derating Factor (Temperature and Voltage)**

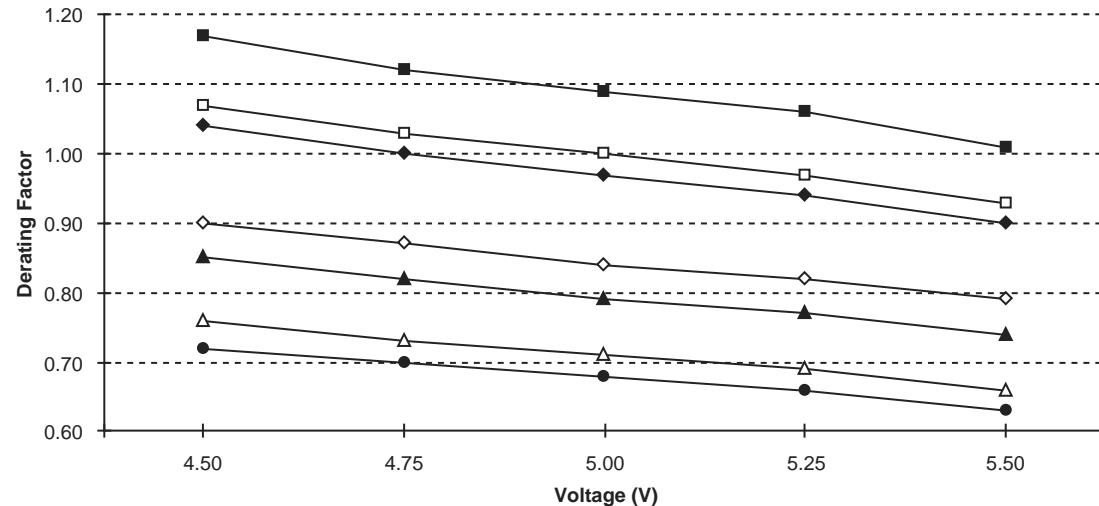
(Commercial Minimum/Maximum Specification) x	Industrial		Military	
	Min.	Max.	Min.	Max.
	0.66	1.07	0.63	1.17

**Table 2-16 • Timing Derating Factor for Designs at Typical Temperature ( $T_J = 25^\circ\text{C}$ ) and Voltage (5.0 V)**

(Commercial Maximum Specification) x	0.85
--------------------------------------	------

**Table 2-17 • Temperature and Voltage Derating Factors  
(normalized to Worst-Case Commercial,  $T_J = 4.75 \text{ V}, 70^\circ\text{C}$ )**

	-55	-40	0	25	70	85	125
<b>4.50</b>	0.72	0.76	0.85	0.90	1.04	1.07	1.117
<b>4.75</b>	0.70	0.73	0.82	0.87	1.00	1.03	1.12
<b>5.00</b>	0.68	0.71	0.79	0.84	0.97	1.00	1.09
<b>5.25</b>	0.66	0.69	0.77	0.82	0.94	0.97	1.06
<b>5.50</b>	0.63	0.66	0.74	0.79	0.90	0.93	1.01



Note: This derating factor applies to all routing and propagation delays.

**Figure 2-18 • Junction Temperature and Voltage Derating Curves  
(normalized to Worst-Case Commercial,  $T_J = 4.75 \text{ V}, 70^\circ\text{C}$ )**

### **A1415A, A14V15A Timing Characteristics (continued)**

**Table 2-20 • A1415A, A14V15A Worst-Case Commercial Conditions, VCC = 4.75 V, TJ = 70°C**

I/O Module – TTL Output Timing <sup>1</sup>		–3 Speed <sup>2</sup>		–2 Speed <sup>2</sup>		–1 Speed		Std. Speed		3.3 V Speed <sup>1</sup>		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t <sub>DHS</sub>	Data to Pad, High Slew		5.0		5.6		6.4		7.5		9.8	ns
t <sub>DLS</sub>	Data to Pad, Low Slew		8.0		9.0		10.2		12.0		15.6	ns
t <sub>ENZHS</sub>	Enable to Pad, Z to H/L, High Slew		4.0		4.5		5.1		6.0		7.8	ns
t <sub>ENZLS</sub>	Enable to Pad, Z to H/L, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t <sub>ENHSZ</sub>	Enable to Pad, H/L to Z, High Slew		6.5		7.5		8.5		10.0		13.0	ns
t <sub>ENLSZ</sub>	Enable to Pad, H/L to Z, Low Slew		6.5		7.5		8.5		10.0		13.0	ns
t <sub>CKHS</sub>	IOCLK Pad to Pad H/L, High Slew		7.5		7.5		9.0		10.0		13.0	ns
t <sub>CKLS</sub>	IOCLK Pad to Pad H/L, Low Slew		11.3		11.3		13.5		15.0		19.5	ns
d <sub>TLHHS</sub>	Delta Low to High, High Slew		0.02		0.02		0.03		0.03		0.04	ns/pF
d <sub>TLHLS</sub>	Delta Low to High, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
d <sub>THLHS</sub>	Delta High to Low, High Slew		0.04		0.04		0.04		0.05		0.07	ns/pF
d <sub>THLLS</sub>	Delta High to Low, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
I/O Module – CMOS Output Timing <sup>1</sup>												
t <sub>DHS</sub>	Data to Pad, High Slew		6.2		7.0		7.9		9.3		12.1	ns
t <sub>DLS</sub>	Data to Pad, Low Slew		11.7		13.1		14.9		17.5		22.8	ns
t <sub>ENZHS</sub>	Enable to Pad, Z to H/L, High Slew		5.2		5.9		6.6		7.8		10.1	ns
t <sub>ENZLS</sub>	Enable to Pad, Z to H/L, Low Slew		8.9		10.0		11.3		13.3		17.3	ns
t <sub>ENHSZ</sub>	Enable to Pad, H/L to Z, High Slew		6.7		7.5		8.5		10.0		13.0	ns
t <sub>ENLSZ</sub>	Enable to Pad, H/L to Z, Low Slew		6.7		7.5		9.0		10.0		13.0	ns
t <sub>CKHS</sub>	IOCLK Pad to Pad H/L, High Slew		8.9		8.9		10.7		11.8		15.3	ns
t <sub>CKLS</sub>	IOCLK Pad to Pad H/L, Low Slew		13.0		13.0		15.6		17.3		22.5	ns
d <sub>TLHHS</sub>	Delta Low to High, High Slew		0.04		0.04		0.05		0.06		0.08	ns/pF
d <sub>TLHLS</sub>	Delta Low to High, Low Slew		0.07		0.08		0.09		0.11		0.14	ns/pF
d <sub>THLHS</sub>	Delta High to Low, High Slew		0.03		0.03		0.03		0.04		0.05	ns/pF
d <sub>THLLS</sub>	Delta High to Low, Low Slew		0.04		0.04		0.04		0.05		0.07	ns/pF

Notes:

1. Delays based on 35 pF loading.
2. The –2 and –3 speed grades have been discontinued. Please refer to the Product Discontinuation Notices (PDNs) listed below:

PDN March 2001

PDN 0104

PDN 0203

PDN 0604

PDN 1004

**A1415A, A14V15A Timing Characteristics (continued)****Table 2-21 • A1415A, A14V15A Worst-Case Commercial Conditions, VCC = 4.75 V, T<sub>J</sub> = 70°C**

Dedicated (hardwired) I/O Clock Network		-3 Speed		-2 Speed		-1 Speed		Std. Speed		3.3 V Speed <sup>1</sup>		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t <sub>IOCKH</sub>	Input Low to High (pad to I/O module input)		2.0		2.3		2.6		3.0		3.5	ns
t <sub>IOPWH</sub>	Minimum Pulse Width High	1.9		2.4		3.3		3.8		4.8		ns
t <sub>IPOWL</sub>	Minimum Pulse Width Low	1.9		2.4		3.3		3.8		4.8		ns
t <sub>IOSAPW</sub>	Minimum Asynchronous Pulse Width	1.9		2.4		3.3		3.8		4.8		ns
t <sub>IOCKSW</sub>	Maximum Skew		0.4		0.4		0.4		0.4		0.4	ns
t <sub>IOP</sub>	Minimum Period	4.0		5.0		6.8		8.0		10.0		ns
f <sub>IOMAX</sub>	Maximum Frequency		250		200		150		125		100	MHz
<b>Dedicated (hardwired) Array Clock</b>												
t <sub>HCKH</sub>	Input Low to High (pad to S-module input)		3.0		3.4		3.9		4.5		5.5	ns
t <sub>HCKL</sub>	Input High to Low (pad to S-module input)		3.0		3.4		3.9		4.5		5.5	ns
t <sub>HPWH</sub>	Minimum Pulse Width High	1.9		2.4		3.3		3.8		4.8		ns
t <sub>HPWL</sub>	Minimum Pulse Width Low	1.9		2.4		3.3		3.8		4.8		ns
t <sub>HCKSW</sub>	Delta High to Low, Low Slew		0.3		0.3		0.3		0.3		0.3	ns
t <sub>HP</sub>	Minimum Period	4.0		5.0		6.8		8.0		10.0		ns
f <sub>HMAX</sub>	Maximum Frequency		250		200		150		125		100	MHz
<b>Routed Array Clock Networks</b>												
t <sub>RCKH</sub>	Input Low to High (FO = 64)		3.7		4.1		4.7		5.5		9.0	ns
t <sub>RCKL</sub>	Input High to Low (FO = 64)		4.0		4.5		5.1		6.0		9.0	ns
t <sub>RPWH</sub>	Min. Pulse Width High (FO = 64)	3.3		3.8		4.2		4.9		6.5		ns
t <sub>RPWL</sub>	Min. Pulse Width Low (FO = 64)	3.3		3.8		4.2		4.9		6.5		ns
t <sub>RCKSW</sub>	Maximum Skew (FO = 128)		0.7		0.8		0.9		1.0		1.0	ns
t <sub>RP</sub>	Minimum Period (FO = 64)	6.8		8.0		8.7		10.0		13.4		ns
f <sub>RMAX</sub>	Maximum Frequency (FO = 64)		150		125		115		100		75	MHz
<b>Clock-to-Clock Skews</b>												
t <sub>I0HCKSW</sub>	I/O Clock to H-Clock Skew	0.0	1.7	0.0	1.8	0.0	2.0	0.0	2.2	0.0	3.0	ns
t <sub>I0RCKSW</sub>	I/O Clock to R-Clock Skew (FO = 64)	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	0.0	3.0	ns
t <sub>HRCKSW</sub>	H-Clock to R-Clock Skew (FO = 64) (FO = 50% maximum)	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	0.0	3.0	ns

Notes:

1. Delays based on 35 pF loading.
2. The -2 and -3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.

**A1425A, A14V25A Timing Characteristics (continued)****Table 2-25 • A1425A, A14V25A Worst-Case Commercial Conditions, VCC = 4.75 V, T<sub>J</sub> = 70°C**

Dedicated (hardwired) I/O Clock Network		-3 Speed <sup>1</sup>		-2 Speed <sup>1</sup>		-1 Speed		Std. Speed		3.3 V Speed <sup>1</sup>		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t <sub>I</sub> OCHH	Input Low to High (pad to I/O module input)		2.0		2.3		2.6		3.0		3.5	ns
t <sub>I</sub> OPWH	Minimum Pulse Width High	1.9		2.4		3.3		3.8		4.8		ns
t <sub>I</sub> POWL	Minimum Pulse Width Low	1.9		2.4		3.3		3.8		4.8		ns
t <sub>I</sub> OSAPW	Minimum Asynchronous Pulse Width	1.9		2.4		3.3		3.8		4.8		ns
t <sub>I</sub> OCKSW	Maximum Skew		0.4		0.4		0.4		0.4		0.4	ns
t <sub>I</sub> OP	Minimum Period	4.0		5.0		6.8		8.0		10.0		ns
f <sub>I</sub> OMAX	Maximum Frequency		250		200		150		125		100	MHz
<b>Dedicated (hardwired) Array Clock</b>												
t <sub>H</sub> CKH	Input Low to High (pad to S-module input)		3.0		3.4		3.9		4.5		5.5	ns
t <sub>H</sub> CKL	Input High to Low (pad to S-module input)		3.0		3.4		3.9		4.5		5.5	ns
t <sub>H</sub> PWH	Minimum Pulse Width High	1.9		2.4		3.3		3.8		4.8		ns
t <sub>H</sub> PWL	Minimum Pulse Width Low	1.9		2.4		3.3		3.8		4.8		ns
t <sub>H</sub> CKSW	Delta High to Low, Low Slew		0.3		0.3		0.3		0.3		0.3	ns
t <sub>H</sub> P	Minimum Period	4.0		5.0		6.8		8.0		10.0		ns
f <sub>H</sub> MAX	Maximum Frequency		250		200		150		125		100	MHz
<b>Routed Array Clock Networks</b>												
t <sub>R</sub> CKH	Input Low to High (FO = 64)		3.7		4.1		4.7		5.5		9.0	ns
t <sub>R</sub> CKL	Input High to Low (FO = 64)		4.0		4.5		5.1		6.0		9.0	ns
t <sub>R</sub> PWH	Min. Pulse Width High (FO = 64)	3.3		3.8		4.2		4.9		6.5		ns
t <sub>R</sub> PWL	Min. Pulse Width Low (FO = 64)	3.3		3.8		4.2		4.9		6.5		ns
t <sub>R</sub> CKSW	Maximum Skew (FO = 128)		0.7		0.8		0.9		1.0		1.0	ns
t <sub>R</sub> P	Minimum Period (FO = 64)	6.8		8.0		8.7		10.0		13.4		ns
f <sub>R</sub> MAX	Maximum Frequency (FO = 64)		150		125		115		100		75	MHz
<b>Clock-to-Clock Skews</b>												
t <sub>I</sub> OHCWSW	I/O Clock to H-Clock Skew	0.0	1.7	0.0	1.8	0.0	2.0	0.0	2.2	0.0	3.0	ns
t <sub>I</sub> ORCWSW	I/O Clock to R-Clock Skew (FO = 64) (FO = 80)	0.0	1.0 0.0	0.0 3.0	1.0 0.0	0.0 3.0	1.0 0.0	0.0 3.0	1.0 0.0	0.0 3.0	3.0 3.0	ns
t <sub>H</sub> RCWSW	H-Clock to R-Clock Skew (FO = 64) (FO = 80)	0.0	1.0 0.0	0.0 3.0	1.0 0.0	0.0 3.0	1.0 0.0	0.0 3.0	1.0 0.0	0.0 3.0	1.0 3.0	ns

Notes:

1. The -2 and -3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
2. Delays based on 35 pF loading.

**A1460A, A14V60A Timing Characteristics (continued)****Table 2-31 • A1460A, A14V60A Worst-Case Commercial Conditions, VCC = 4.75 V, T<sub>J</sub> = 70°C**

I/O Module Input Propagation Delays		-3 Speed <sup>1</sup>		-2 Speed <sup>1</sup>		-1 Speed		Std. Speed		3.3 V Speed <sup>1</sup>		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t <sub>INY</sub>	Input Data Pad to Y		2.8		3.2		3.6		4.2		5.5	ns
t <sub>ICKY</sub>	Input Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t <sub>OCKY</sub>	Output Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t <sub>ICLRY</sub>	Input Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
t <sub>OCLRY</sub>	Output Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
<b>Predicted Input Routing Delays<sup>2</sup></b>												
t <sub>RD1</sub>	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t <sub>RD2</sub>	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t <sub>RD3</sub>	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t <sub>RD4</sub>	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t <sub>RD8</sub>	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
<b>I/O Module Sequential Timing (wrt IOCLK pad)</b>												
t <sub>INH</sub>	Input F-F Data Hold	0.0		0.0		0.0		0.0		0.0		ns
t <sub>INSU</sub>	Input F-F Data Setup	1.3		1.5		1.8		2.0		2.0		ns
t <sub>IDEH</sub>	Input Data Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t <sub>IDESU</sub>	Input Data Enable Setup	5.8		6.5		7.5		8.6		8.6		ns
t <sub>OUTH</sub>	Output F-F Data hold	0.7		0.8		0.9		1.0		1.0		ns
t <sub>OUTSU</sub>	Output F-F Data Setup	0.7		0.8		0.9		1.0		1.0		ns
t <sub>ODEH</sub>	Output Data Enable Hold	0.3		0.4		0.4		0.5		0.5		ns
t <sub>ODESU</sub>	Output Data Enable Setup	1.3		1.5		1.7		2.0		2.0		ns

Notes:

5. The -2 and -3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
6. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

**A14100A, A14V100A Timing Characteristics (continued)****Table 2-35 • A14100A, A14V100A Worst-Case Commercial Conditions, VCC = 4.75 V, TJ = 70°C**

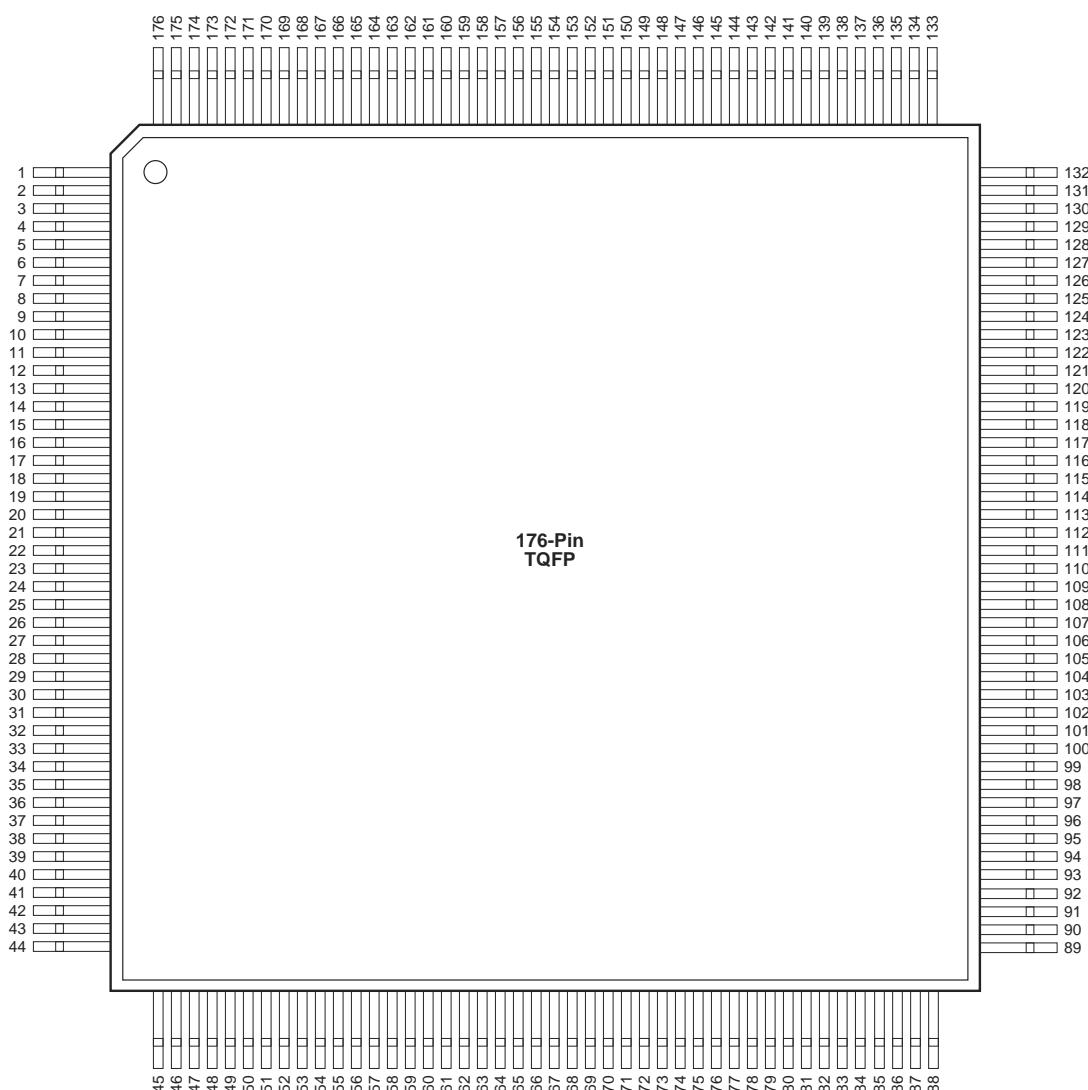
I/O Module Input Propagation Delays		-3 Speed <sup>1</sup>		-2 Speed <sup>1</sup>		-1 Speed		Std. Speed		3.3 V Speed <sup>1</sup>		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t <sub>INY</sub>	Input Data Pad to Y		2.8		3.2		3.6		4.2		5.5	ns
t <sub>ICKY</sub>	Input Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t <sub>OCKY</sub>	Output Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t <sub>ICLRY</sub>	Input Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
t <sub>OCLRY</sub>	Output Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
<b>Predicted Input Routing Delays<sup>2</sup></b>												
t <sub>RD1</sub>	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t <sub>RD2</sub>	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t <sub>RD3</sub>	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t <sub>RD4</sub>	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t <sub>RD8</sub>	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
<b>I/O Module Sequential Timing (wrt IOCLK pad)</b>												
t <sub>INH</sub>	Input F-F Data Hold	0.0		0.0		0.0		0.0		0.0		ns
t <sub>INSU</sub>	Input F-F Data Setup	1.2		1.4		1.5		1.8		1.8		ns
t <sub>IDEH</sub>	Input Data Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t <sub>IDESU</sub>	Input Data Enable Setup	5.8		6.5		7.5		8.6		8.6		ns
t <sub>OUTH</sub>	Output F-F Data hold	0.7		0.8		1.0		1.0		1.0		ns
t <sub>OUTSU</sub>	Output F-F Data Setup	0.7		0.8		1.0		1.0		1.0		ns
t <sub>ODEH</sub>	Output Data Enable Hold	0.3		0.4		0.5		0.5		0.5		ns
t <sub>ODESU</sub>	Output Data Enable Setup	1.3		1.5		2.0		2.0		2.0		ns

Notes: \*

1. The -2 and -3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.



<b>PQ160</b>			
<b>Pin Number</b>	<b>A1425, A14V25 Function</b>	<b>A1440, A14V40 Function</b>	<b>A1460, A14V60 Function</b>
1	GND	GND	GND
2	SDI, I/O	SDI, I/O	SDI, I/O
5	NC	I/O	I/O
9	MODE	MODE	MODE
10	VCC	VCC	VCC
14	NC	I/O	I/O
15	GND	GND	GND
18	VCC	VCC	VCC
19	GND	GND	GND
20	NC	I/O	I/O
24	NC	I/O	I/O
27	NC	I/O	I/O
28	VCC	VCC	VCC
29	VCC	VCC	VCC
40	GND	GND	GND
41	NC	I/O	I/O
43	NC	I/O	I/O
45	NC	I/O	I/O
46	VCC	VCC	VCC
47	NC	I/O	I/O
49	NC	I/O	I/O
51	NC	I/O	I/O
53	NC	I/O	I/O
58	PRB, I/O	PRB, I/O	PRB, I/O
59	GND	GND	GND
60	VCC	VCC	VCC
62	HCLK, I/O	HCLK, I/O	HCLK, I/O
63	GND	GND	GND
74	NC	I/O	I/O
75	VCC	VCC	VCC
76	NC	I/O	I/O
77	NC	I/O	I/O
78	NC	I/O	I/O
79	SDO	SDO	SDO
80	IOPCL, I/O	IOPCL, I/O	IOPCL, I/O
81	GND	GND	GND
90	VCC	VCC	VCC
91	VCC	VCC	VCC

**TQ176**

Note: This is the top view.

**Note**

For Package Manufacturing and Environmental information, visit the Resource Center at  
<http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

TQ176		
Pin Number	A1440, A14V40 Function	A1460, A14V60 Function
1	GND	GND
2	SDI, I/O	SDI, I/O
10	MODE	MODE
11	VCC	VCC
20	NC	I/O
21	GND	GND
22	VCC	VCC
23	GND	GND
32	VCC	VCC
33	VCC	VCC
44	GND	GND
49	NC	I/O
51	NC	I/O
63	NC	I/O
64	PRB, I/O	PRB, I/O
65	GND	GND
66	VCC	VCC
67	VCC	VCC
69	HCLK, I/O	HCLK, I/O
82	NC	I/O
83	NC	I/O
87	SDO	SDO
88	IOPCL, I/O	IOPCL, I/O

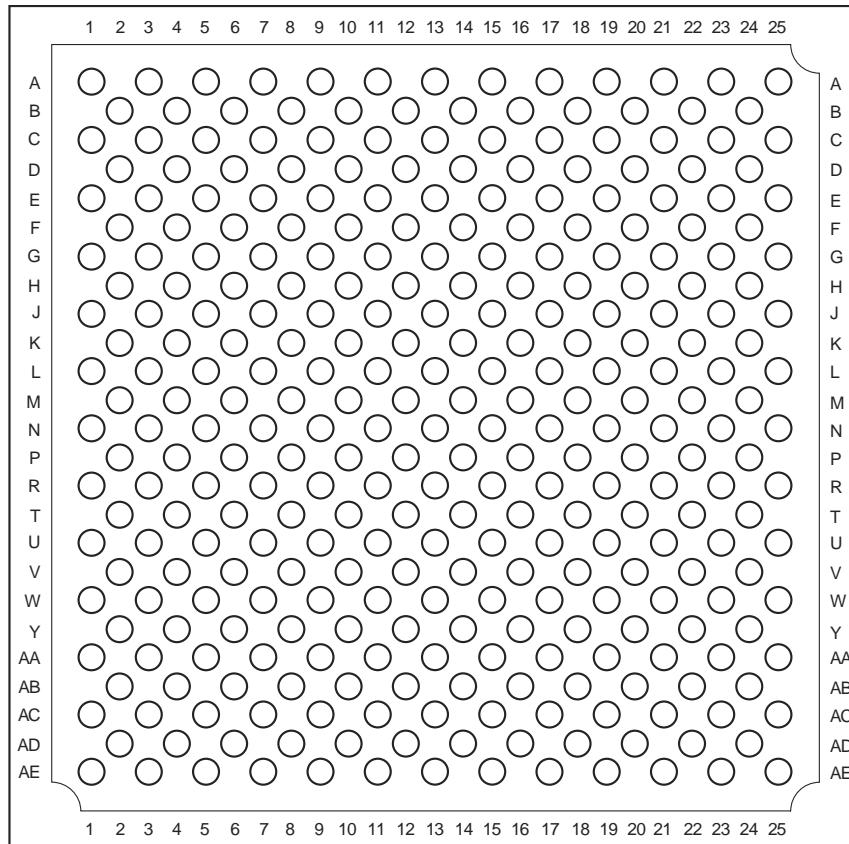
TQ176		
Pin Number	A1440, A14V40 Function	A1460, A14V60 Function
89	GND	GND
98	VCC	VCC
99	VCC	VCC
108	GND	GND
109	VCC	VCC
110	GND	GND
119	NC	I/O
121	NC	I/O
122	VCC	VCC
123	GND	GND
124	VCC	VCC
132	IOCLK, I/O	IOCLK, I/O
133	GND	GND
138	NC	I/O
152	CLKA, I/O	CLKA, I/O
153	CLKB, I/O	CLKB, I/O
154	VCC	VCC
155	GND	GND
156	VCC	VCC
157	PRA, I/O	PRA, I/O
158	NC	I/O
170	NC	I/O
176	DCLK, I/O	DCLK, I/O

**Notes:**

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

## BG313

---

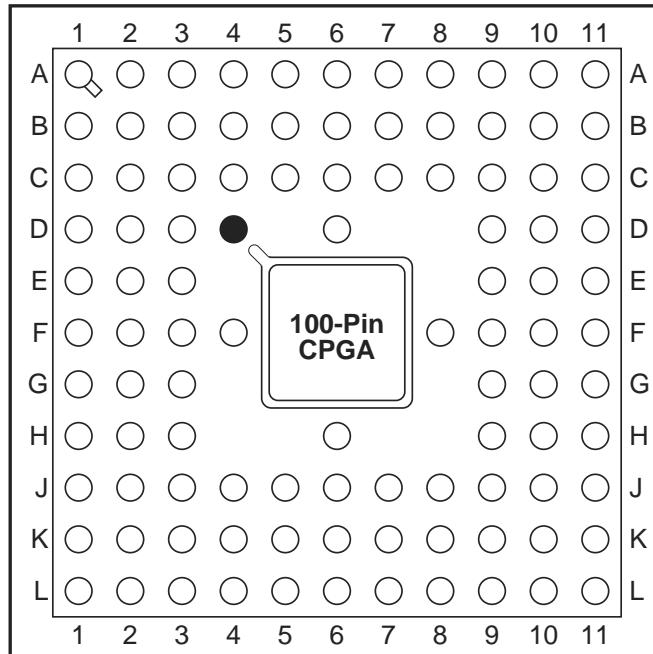


*Note: This is the top view.*

---

### Note

For Package Manufacturing and Environmental information, visit the Resource Center at  
<http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

**PG100**

● Orientation Pin

Note: This is the top view.

**Note**

For Package Manufacturing and Environmental information, visit the Resource Center at  
<http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

PG175	
A1440 Function	Location
CLKA or I/O	C9
CLKB or I/O	A9
DCLK or I/O	D5
GND	D4, D8, D11, D12, E4, E14, H4, H12, L4, L12, M4, M8, M12
HCLK or I/O	R8
IOCLK or I/O	E12
IOPCL or I/O	P13
MODE	F3
NC	A1, A2, A15, B2, B3, P2, P14, R1, R2, R14, R15
PRA or I/O	B8
PRB or I/O	R7
SDI or I/O	D3
SDO	N12
VCC	C3, C8, C13, E15, H3, H13, L1, L14, N3, N8, N13

*Notes:*

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.
4. The PG175 package has been discontinued.